

ISO/IEC 18047-6:2017-10 (E)

Information technology - Radio frequency identification device conformance test method s - Part 6: Test methods for air interface communications at 860 MHz to 960 MHz

Contents		Page
Foreword		vi
Introduction		vii
1	Scope	1
2	Normative references	1
3	Terms, definitions, symbols and abbreviated terms	2
4	Default conditions applicable to the test methods	3
4.1	Test environment	3
4.2	Pre-conditioning	3
4.2.1	General	3
4.2.2	Default tolerance	3
4.2.3	Noise floor at test location	3
4.2.4	Total measurement uncertainty	3
5	Setup of test equipment	4
5.1	Setup of test equipment for interrogator tests	4
5.1.1	General	4
5.1.2	Sense antenna	4
5.2	Setup of test equipment for tag tests	5
5.2.1	General	5
6.1	Functional tests of interrogator	6
6.1.1	Interrogator modulation test	6
6.1.2	Interrogator demodulation and turn-around time	7
6.2	Functional tests of tag	8
6.2.1	Tag demodulation and turn-around time	8
6.2.2	Tag backscatter	8
6.2.3	Tag response time	9
6.2.4	Tag bit rate	10
6.2.5	Tag state storage time	10
7.1	Functional tests of interrogator	11
7.1.1	Interrogator modulation test	11
7.1.2	Interrogator demodulation and turn-around time	12
7.2	Functional tests of tag	12
7.2.1	Tag demodulation and turn-around time	12
7.2.2	Tag backscatter	13
7.2.3	Tag response time	14
7.2.4	Tag bit rate	15
7.2.5	Tag state storage time	15
8.1	Functional tests of interrogator	16
8.1.1	Interrogator data encoding	16
8.1.2	Interrogator RF envelope parameters	17
8.1.3	Interrogator RF power-up and power-down parameters	18

8.1.4	Interrogator preamble parameters	19
8.1.5	Interrogator link timing T2	20
8.1.6	Interrogator link timing T3	21
8.1.7	Interrogator link timing T4	22
8.2	Functional tests of tag	23
8.2.1	Tag frequency range	23
8.2.2	Tag demodulation capability	24
8.2.3	Tag duty cycle	25
8.2.4	Tag preamble	26
8.2.5	Tag link frequency tolerance and variation	28
8.2.6	Tag link timing T1	29
8.2.7	Tag link timing T2	30
8.2.8	Tag link timing T5	31
8.2.9	Tag link timing T6	32
8.2.10	Tag link timing T7	33
8.2.11	Tag state diagram	34
8.2.12	Tag backscatter (optional)	36
8.3	Additional protocol related tests	37
8.3.1	Memory overruns	37
8.3.2	Kill command	38
8.3.3	Unauthorized Write command	38
8.3.4	Optional commands and features	39
9.1	Functional tests of interrogator	42
9.1.1	Interrogator modulation test	42
9.1.2	Interrogator demodulation and data decoding	42
9.2	Functional tests of tag	44
9.2.1	General	44
9.2.2	Data encoding	45
9.2.3	Link bits	46
9.2.4	Tag timing parameters	46
9.2.5	Tag bit rate	47
9.2.6	Tag multi-page timing	48
9.2.7	Tag LBT	48
10.1	Tag functional tests	49
10.1.1	Battery-assisted passive tag persistence time test	49
	passive (BAP)	50
11.1	Functional tests of interrogator	50
11.1.1	Interrogator RF envelope parameters	50
11.1.2	Interrogator activation minimum dwell time, TA	51
11.1.3	Interrogator link timing T2	52
11.1.4	Interrogator link timing T3	54
11.1.5	Interrogator link timing T4	55
11.2	Functional tests of tag	56
11.2.1	Tag demodulation capability	56
11.2.2	Tag link frequency tolerance and variation	57
11.2.3	Tag link timing T1	58
11.2.4	Tag link timing T2	59
11.2.5	Tag activation time maximum, TA	60
11.2.6	Tag stateful hibernate timer	61
12.1	Tag functional tests	63
12.1.1	Simple sensor test	63
13	Full-function sensor test	64
13.1	Purpose	64
13.2	Procedure	64
13.2.1	General	64

Annex A (informative) Test measurement site	65
Annex B (normative) Command coding for conformance tests for the different types of ISO/ IEC 18000-6	77
Annex C (normative) Technical performance of the generic electronic test instruments	78
Annex D (normative) Tag emulator	79
Annex E (informative) Measurement examples	81
Bibliography	82